


<b>Search Notes</b>  	<b>Application/Control No.</b>  10710600	<b>Applicant(s)/Patent Under Reexamination</b>  FUJISAKI, IWAO
	<b>Examiner</b>  DAVID Q NGUYEN	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	556.1	04/21/09	DN
370	338	04/21/09	DN

SEARCH NOTES		
Search Notes	Date	Examiner
Text search	04/21/09	DN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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